

Model #	Previous Model #	Function	Description	Chip Size Range	Temperature Range	Frequency Range	Primary Application
Test Tweezers							
351	351	C/DF	short format, 2 standard electrodes per contact, 0.015" thick	0402 - 1812	0 - 55°C	up to 110 MHz	General purpose testing of MLCC's for C/DF
352	352	C/DF	long format, 2 standard electrodes per contact, 0.015" thick, angled mounting block	0402 - 4044	0 - 55°C	up to 110 MHz	General purpose testing of large MLCC,s for C/DF
353	353	C/DF	short format, 1 micro electrode per contact, 0.015" thick	01005 - 1812	0 - 55°C	up to 110 MHz	General purpose testing of small MLCC's, down to 01005
3504	354A	ACR	Kelvin Tweezers, short format, 2 standard electrodes per contact, 0.015" thick, Kelvin insulator	0805 - 1812	0 - 55°C	1 KHz	Testing milli-ohm resistance of chip inductors, inductor beads, etc.
3505	356	ACR	Kelvin Tweezers, short format, 2 micro electrodes per contact, 0.008" thick, Kelvin insulator	0402 - 1812	0-55°C	1 KHz	Testing milli-ohm resistance of chip inductors, inductor beads, etc.
3506	354B	DCR	Kelvin Tweezers, short format, 2 standard electrodes per contact, 0.015" thick, Kelvin insulator	0805 - 1812	0 - 55°C	DC	DCR testng of chip resistors, chip fuses, chip inductors and other chip devices
3507	none	100 KHZ ESR	Kelvin tweezers, short format, 4 sharp pointed electrodes per contact (redundant Kelvin), 0.008" thick, Kelvin spacers 0.008" thick	All Tantalum surface mount case sizes	0 - 55°C	100KHz	100 KHz ESR testing of Tantalum chip capacitors that are mounted on a circuit board
3508	357	C/DF	short format, replaceable needle tip electrodes	0402 to 1812	0 - 55°C	up to 110 MHz	C/DF testing of chips in a tape/reel pack, also for testing discoidal capacitors and linear capacitor arrays
3509	358	C/DF	long format, replaceable needle tip electrodes, angled mounted block	0402 to 4440	0 - 55°C	up to 110 MHz	C/DF testing of chips in a tape/reel pack, can also be equipped for testing chips with 2 terminations on one surface of a chip
3510	361A	IR	short format, 2 standard electrodes per contact, connectors for 4349A/B	0402 to 1812	0 - 55°C	DC	IR testing of MLCC, 1000V max.
3511	361B	IR	short format, 2 standard electrodes per contact, banana connectors	0402 to 1812	0 - 55°C	DC	IR testing of MLCC, 1000V max.

3512	362A	IR	long format, 2 compliant standard electrodes per contact, connectors for 4339A/B	0402 to 4440	0 - 55°C	DC	IR testing of MLCC, 1000V max.
3514	363	IR	short format, 1 micro electrode per contact, 0.015" thick, banana connectors	01005 to 1812	0 - 55°C	DC	IR testing of MLCC, 1000V max.
3515	363A	IR	short format, 1 micro electrode per contact, 0.015" thick, connectors for 4339A/B	01005 to 1812	0 - 55°C	DC	IR testing of MLCC, 1000V max.
3516	361C	IR	short format, 2 standard electrodes per contact, 0.015" thick, connectors for B2985A, B2987A	0402 to 1812	0 - 55°C	DC	IR testing of MLCC, 1000V max.
3517	364	IR	short format, 1 micro electrode per contact, connectors for B2985A, B2987A	01005 to 1812	0 - 55°C	DC	IR testing of MLCC, 1000V max.
3525	none	C/DF	long format, wide mounting block, 4 compliant electrodes per contact, used for very large chips	very large chips, mostly used for stacks	0 - 55°C	up to 110 MHz	General purpose testing of large MLCC,s for C/DF
3527	354	DCR	Kelvin Tweezers, long format, 2 standard electrodes per contact, 0.015" thick, Kelvin insulator	0603 - 4440	0 - 55°C	DC	DCR testng of chip resistors, chip fuses, chip inductors and other chip devices
3528	355	DCR	Kelvin Tweezers, long format, 2 micro electrodes per contact, 0.008" thick, Kelvin insulators. Shrouded banana connectors	0603 - 4440	0 - 55°C	DC	DCR testng of chip resistors, chip fuses, chip inductors and other chip devices
3529	none	DWV	long format, angled mounting block, no cladding on legs, 2 electrodes per contact, needle tip electrodes with no diameter reduction	DWV on large DUT's	0 - 55°C	DC	DWV testing of chip DUT's
3531	none	IR	long format, wide mounting block, 4 compliant electrodes per contact, used for very large chips	very large chips, mostly used for stacks	0 - 55°C	IR	IR testing of large MLCC
3532	none	IR	long format, needle electrodes, angled mounting block	0201 to 4440	0 - 55°C	IR	IR testing of MLCC
3533	none	IR	long format, wide mounting block, 4 electrodes per contact, used for very large chips	very large chips, mostly used for stacks	0 - 55°C	IR	IR testing of large MLCC

3534	none	IR	long format, needle electrodes, angled mounting block	0201 to 4440	0 - 55°C	IR	IR testing of MLCC
3535	none	ACR	long format, two standard Kelvin electrodes per contact, BNC connectors	0603 - 4440	0 - 55°C	ACR	Testing milli-ohm resistance of chip inductors, inductor beads, etc.
3536	none	IR	long format, two standard electrodes per contact, slanted end block, banana connectors	0603 to 4440	0 - 55°C	IR	IR testing of MLCC
3537	none	IR	short format, needle electrodes	01005 to 1206	0 - 55°C	IR	IR testing of MLCC chips
3538	none	C/DF	short format, needle electrodes	01005 to 1206	0 - 55°C	C/DF	C/DF testing of MLCC chips
3539	none	IR	short format, needle electrodes	01005 to 1206	0 - 55°C	IR	IR testing of MLCC chips
Self Closing Test Tweezers							
3519	381	C/DF	self retaining tweezers with cabeling	0402 to 4440 MLCC's, all Tantalum case sizes	-55°C - 125°C	up to 110 MHz	temperature testing of MLCC's, Tantalum chips and other chip components
3520	382	IR	self retaining tweezers with cabeling	0402 to 4440 MLCC's, all Tantalum case sizes	-55°C - 125°C	DC	temperature testing of MLCC's, Tantalum chips and other chip components
3521	383	IR	self retaining tweezers with cabeling	0402 to 4440 MLCC's, all Tantalum case sizes	-55°C - 125°C	DC	temperature testing of MLCC's, Tantalum chips and other chip components
3522	384	DCR	self retaining tweezers with cabeling	0402 to 4440 MLCC's, all Tantalum case sizes	-55°C - 125°C	DC	temperature testing of MLCC's, Tantalum chips and other chip components
3523	none	ACR	self retaining tweezers with cabeling	0402 to 4440 MLCC's, all Tantalum case sizes	-55°C - 125°C	1 KHz	temperature testing of MLCC's, Tantalum chips, chip inductors, inductor beads and other chip
3524	none	100 KHZ ESR	self retaining tweezers with cabeling, redundant Kelvin contacts	0402 to 4440 MLCC's, all Tantalum case sizes	-55°C - 125°C	100 KHz	100 KHZ ESR testing of Tantalum chip capacitors, MLCC's and other chip componentss
3526	none	100 KHZ ESR	self retaining tweezers with cabeling, redundant Kelvin contacts	0402 to 4440 MLCC's, all Tantalum case sizes	-55°C - 165°C	100 KHz	100 KHZ ESR testing of Tantalum chip capacitors, MLCC's and other chip componentss

3530	none	DCR	self retaining tweezers with cabling	0402 to 4440 MLCC's, all Tantalum case sizes	-55°C - 125°C	DC	IR testing of MLCC, 1000V max.
SLC test sets							
3600	none	C/DF	SLC test set, includes hand held probe and base electrode, cabling	All SLC chip sizes	0 - 55°C	1 KHz to 1 MHz	C/DF testing of SLC's
3600BE	none	C/DF	replacement base electrode for 3600	All SLC chip sizes	0 - 55°C		C/DF testing of SLC's
3601	none	IR	SLC test set, includes hand held probe and base electrode, cabling	All SLC chip sizes	0 - 55°C	DC	IR testing of SLC's
3601BE	none	C/DF	replacement base electrode for 3601	All SLC chip sizes		DC	C/DF testing of SLC's
3602	none	IR	SLC test set, includes hand held probe and base electrode, cabling	All SLC chip sizes	0 - 55°C	DC	IR testing of SLC's
3602BE	none	C/DF	replacement base electrode for 3602	All SLC chip sizes	0 - 55°C	DC	C/DF testing of SLC's
3603	none	IR	SLC test set, includes hand held probe and base electrode, cabling	All SLC chip sizes	0 - 55°C	DC	IR testing of SLC's
3603BE	none	IR	replacement base electrode for 3603	All SLC chip sizes	0 - 55°C	DC	C/DF testing of SLC's
3604	none	IR	SLC test set, includes hand held probe and base electrode, cabling	All SLC chip sizes	0 - 55°C	DC	IR meters equipped with banana connectors, including IET1864, IET 1865,
3604BE	none	IR	replacement base electrode for 3604	All SLC chip sizes	0 - 55°C	1 KHz to 1 MHz	C/DF testing of SLC's
3605	none	ALL	Probe stand for open and short compensation	All SLC chip sizes	0 - 55°C	DC	C/DF testing of SLC's
3607	none	C/DF	SLC test set for chips mounted on ceramic substrate	All SLC chip sizes	0 - 55°C	1 KHz to 1 MHz	C/DF testing of SLC's
3608	none	IR	SLC test set for chips mounted on ceramic substrate	All SLC chip sizes	0 - 55°C	DC	IR testing of SLC's

3608BE	none	IR	replacement base electrode for 3608	All SLC chip sizes	0 - 55°C	DC	IR testing of SLC's
3609	none	C/DF	Precision SLC pivot test set	All Gap Cap style chip sizes	0 - 55°C	1 KHz to 1 MHz	C/DF testing of Gap Cap style chips
3610	none	IR	Precision SLC pivot test set	All Gap Cap style chip sizes	0 - 55°C	DC	IR testing of Gap Cap style chips
3611	none	IR	Precision SLC pivot test set	All Gap Cap style chip sizes	0 - 55°C	DC	IR testing of Gap Cap style chips
3612	none	C/DF	Precision SLC test set	All SLC chip sizes	0 - 55°C	1 KHz to 1 MHz	C/DF testing of SLC chips
3613	none	C/DF	Precision SLC test set with compliant contact	All SLC chip sizes	0 - 55°C	1 KHz to 1 MHz	C/DF testing of SLC chips
3614	none	IR	Precision SLC test set with compliant contact	All SLC chip sizes	0 - 55°C	DC	IR testing of SLC chips
3615	none	IR	Precision SLC test set with compliant contact	All SLC chip sizes	0 - 55°C	DC	IR testing of SLC chips
Hand held probes							
3606	none	Kelvin DCR	hand held probe, two can be used to probe components, circuit boards, etc	All chip sizes, plus circuit boards, etc.	0 - 55°C	DC	DCR testing of components and other devices
Instrument Mounted Fixtures							
5720	572	C/DF	instrument mounted fixture for testing MLCC	01005 to 4044	0 - 55°C	up to 40 MHz	C/DF testing of MLCC
5740	574	C/DF	instrument mounted fixture for testing axial and radial leaded capacitors	Radial and Axial leaded components up to 2" long,	0 - 55°C	up to 40 MHz	C/DF testing of leaded components
5741	none	ACR, 100 KHZ ESR	instrument mounted fixture for testing axial and radial leaded capacitors	Radial and Axial leaded components up to 2" long,	0 - 55°C	up to 100 KHz	AC resistance (4338A/B) of axial or radial leaded components
5702	573	C/DF	instrument mounted fixture for testing MLCC, modular design with replaceable contacts	0201 up to 1812	0 - 55°C	up to 110 MHz	Efficient low volume production testing of MLCC

			Bench Fixtures				
5742	550	DCR	Bench fixture with modular Kelvin contacts, 2 adjustable axis and banana connectors	0402 up to 1812	0 - 55°C	DC	DCR of chip components
5743	none	IR	IR testing of leaded capacitors, equipped with connectors that mate with 4339AB meters, includes interlock connector. Mounted inside a shielded metal box for operatr safety. Two axis.	Radial and Axial leaded components up to 2" long,	0 - 55°C	DC	Insulation resistance of leaded capacitors and other components
5744	none	IR	IR testing of leaded capacitors, equipped with connectors that mate with B2985A and B2987A meters, includes interlock connector. Mounted inside a shielded metal box for operatr safety. Two axis	Radial and Axial leaded components up to 2" long,	0 - 55°C	DC	Insulation resistance of leaded capacitors and other components
5745	none	IR	IR testing of leaded capacitors, equipped with connectors that mate with IET 1865 meters, includes interlock connector. Mounted inside a shielded metal box for operatr safety.	Radial and Axial leaded components up to 2" long,	0 - 55°C	DC	Insulation resistance of leaded capacitors and other components
5746	none	IR	IR testing of leaded capacitors, equipped with connectors that mate with IET 1864 meters. Mounted inside a shielded metal box for operatr safety.	Radial and Axial leaded components up to 2" long,	0 - 55°C	DC	Insulation resistance of leaded capacitors and other components
5747	570	C/DF	Bench fixture, 2 adjustable axis, modular contact and quick disconnect	MLCC 01005 to 4440	0 - 55°C	50 Hz to 1 MHz	C/DF testing of MLCC
5748			not assigned				
5749	560A	IR	Bench fixture with two adjustable axis, shielded box, interlock switch, connectors for Agilent 4339A/B	0201 to large	0 - 55°C	DC	IR testing of chip components
5750	560B	IR	Bench fixture with two adjustable axis, shielded box, interlock switch, banana connectors	0201 to large	0 - 55°C	DC	IR testing of chip components

5751	560C	IR	Bench fixture with two adjustable axis, shielded box, interlock switch, connectors for B2985A, B2087A	0201 to large	0 - 55°C	DC	IR testing of chip components
5752	571, MTF	C/DF	Bench fixture, 3 adjustable axis, modular contact and quick disconnect	MLCC 01005 to 4440	0 - 55°C	50 Hz to 1 MHz	C/DF testing of MLCC
5753	none	C/DF	Bench fixture, 3 adjustable axis, modular contact, quick disconnect	0201 to large	0 - 55°C	50 Hz to 1 MHz	C/DF testing of chip components
5754	none	Kelvin DCR	Bench fixture, 3 adjustable axis, modular contact and quick disconnect, banana connectors	0201 to large	0 - 55°C	DC to 1MHZ	Kelvin DCR testing chip components
5755	none	IR	Bench fixture, 3 adjustable axis, modular contacts and quick disconnect, shielded box and interlock switch	0201 to large	0 - 55°C	50 Hz to 1 MHz	IR testing of chip components
5756	none	IR	Bench fixture, 3 adjustable axis, modular contacts and quick disconnect, shielded box and interlock switch	0201 to large	0 - 55°C	DC	IR testing of chip components
5757	none	IR	Bench fixture, 3 adjustable axis, modular contacts and quick disconnect, shielded box and interlock switch	0201 to large	0 - 55°C	DC	IR testing of chip components
5758			not assigned				
5759	none	C/DF	Pivot Fixture, three adjustable axis	All Gap Cap type chips	0 - 55°C	1Khz to 1MHz	C/DF testing of Gap Cap chips and other DUT's with two or more terminations on one surface
5760	none	IR	Pivot Fixture, three adjustable axis	All Gap Cap type chips	0 - 55°C	DC	IR testing of Gap Cap chips and other DUT's with two or more terminations on one surface
5761	none	IR	Pivot Fixture, three adjustable axis	All Gap Cap type chips	0 - 55°C	DC	IR testing of Gap Cap chips and other DUT's with two or more terminations on one surface

5762	none	DCR	Pivot Fixture, three adjustable axis	All SMD sizes	0 - 55°C	DC	DCR testing of chip resistors and other DUT's with two terminations on one surface
5763	550A	ACR	Bench fixture with three adjustable axis, BNC connectors, modular Kelvin contacts	0201 to large	0 - 55°C	50HZ to 100KHZ	Kelvin ACR testing chip components
Hand Held IR Fixtures							
4339-110	4339-110	IR	Low noise test leads	All SMD sizes, other DUT's	0 - 55°C	dc	IR testing of SMD chips and and other DUT's
2985-100	2985-100	IR	Low noise test leads	All SMD sizes, other DUT's	0 - 55°C	DC	IR testing of SMD chips and and other DUT's

Applicable Instruments	Similar HP, Agilent, Keysight Fixtures
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	16334A
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
4338B	none
4338B	none
3458A, 34401A, 34460A, 34461A, 34465A, 34470A, other DCR meters, DC milli-ohm meters and DC micro-ohm meters utilizing banana connectors	none
4263B, other meters capable of 100 KHz ESR testing	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
4339A/B	16118A
GR 1864, GR 1685, HP 4329A, Beckman L7, Beckman L8	none

4339A, 4339B	none
GR 1864, GR 1685, HP 4329A, Beckman L7, Beckman L8	none
4339A, 4339B	
B2985A, B2987A	16118A
B2985A, B2987A	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
3458A, 34401A, 34460A, 34461A, 34465A, 34470A, other DCR meters, DC milli-ohm meters and DC micro- ohm meters utilizing banana connectors	none
3458A, 34401A, 34460A, 34461A, 34465A, 34470A, other DCR meters, DC milli-ohm meters and DC micro- ohm meters utilizing shrouded banana connectors	none
Vitretek DWV meters	none
4339A, 4339B	none
4339A, 4339B	none
B2985A, B2987A	none

B2985A, B2987A	none
4338B	none
GR 1864, GR 1865, HP 4329A, Beckman L7, Beckman L8	none
4339A, 4339B	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
GR 1864, GR 1865, HP 4329A, Beckman L7, Beckman L8	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
4339A, 4339B	none
B2985A, B2987A	none
3458A, 34401A, 34460A, 34461A, 34465A, 34470A, other DCR meters, DC milli-ohm meters and DC micro- ohm meters utilizing banana connectors	none
4338B	none
4263B, other meters capable of 100 KHz ESR testing	none
4263B, other meters capable of 100 KHz ESR testing	none

GR 1864, GR 1685, HP 4329A, Beckman L7, Beckman L8	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
4339A, 4339B	none
4339A, 4339B	
B2985A, B2987A	none
B2985A, B2987A	none
IR meters equipped with banana connectors, including IET1864, IET 1865,	none
IR meters equipped with banana connectors, including IET1864, IET 1865,	none
IR meters equipped with banana and BNC connectors, including HP 43429A	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
IR meters equipped with banana connectors, including IET1864, IET 1865,	none

IR meters equipped with banana connectors, including IET1864, IET 1865,	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
B2985A, B2987A	none
4339A/B	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
4339A/B	none
B2985A, B2987A	none
3458A, 34401A, 34460A, 34461A, 34465A, 34470A, other DCR meters, DC milli-ohm meters and DC micro-ohm meters utilizing banana connectors	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	16034E, 16034G
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	16047A, 16047E
4263B, E4980A, E4981A, 4275A, 4338B	16047A, 16047E
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none

3458A, 34401A, 34460A, 34461A, 34465A, 34470A, other DCR meters, DC milli-ohm meters and DC micro-ohm meters utilizing banana connectors	none
4339A / B	none
B2985A, B2987A	none
IET 1865	none
IET 1864	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
Agilent 4339A / B	16039A, obsolete, no replacement
IET 1685, 1685+	none

Keysight B2985A, B2987A	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
3458A, 34401A, 34460A, 34461A, 34465A, 34470A, other DCR meters, DC milli-ohm meters and DC micro- ohm meters utilizing banana connectors	none
Agilent 4339A / B	none
Keysight B2985A, B2987A	none
IET 1865	none
4278A, 4263, 4268, 4288, E4980A, E4981A, E4980AL, 4284A, 4285A, 4294A	none
B2985A, B2987A	none
4339A / B	none

3458A, 34401A, 34460A, 34461A, 34465A, 34470A, other DCR meters, DC milli-ohm meters and DC micro- ohm meters utilizing banana connectors	none
4338A, 4263B	none
4339A / B	16117B
B2985A, B2987A	N1425A